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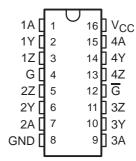
- Meet or Exceed the Requirements of TIA/EIA-422-B and ITU Recommendation V.11
- Low Power, I<sub>CC</sub> = 100 μA Typ
- Operate From a Single 5-V Supply
- High Speed, t<sub>PLH</sub> = t<sub>PHL</sub> = 7 ns Typ
- Low Pulse Distortion, t<sub>Sk(p)</sub> = 0.5 ns Typ
- High Output Impedance in Power-Off Conditions
- Improved Replacement for AM26LS31

### description

The AM26C31C, AM26C31I, and AM26C31M are four complementary-output line drivers designed to meet the requirements of TIA/EIA-422-B and ITU (formerly CCITT). The 3-state outputs have high-current capability for driving balanced lines, such as twisted-pair or parallel-wire transmission lines, and they provide the high-impedance state in the power-off condition. The enable function is common to all four drivers and offers the choice of an active-high or active-low enable input. BiCMOS circuitry reduces power consumption without sacrificing speed.

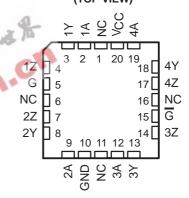
The AM26C31C is characterized for operation from 0°C to 70°C, the AM26C31I is characterized for operation from -40°C to 85°C, and the AM26C31M is characterized for operation from -55°C to 125°C.

#### AM26C31C, AM26C31I . . . D, DB<sup>†</sup>, OR N PACKAGE AM26C31M . . . J OR W PACKAGE (TOP VIEW)



†The DB package is only available left-ended taped (order AM26C31IDBLE or AM26C31CDBLE).

# AM26C31M . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

# FUNCTION TABLE (each driver)

INPUT	ENA	BLES	OUTPUTS		
Α	G	G	Υ	Z	
Н	Н	Х	Н	L	
L	Н	Χ	L	Н	
Н	Х	L	Н	L	
L	Х	L	L	Н	
Х	L	Н	z	Z	

H = high level, L = low level, X = irrelevant,

Z = high impedance (off)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

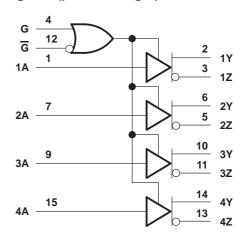


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# logic symbol†

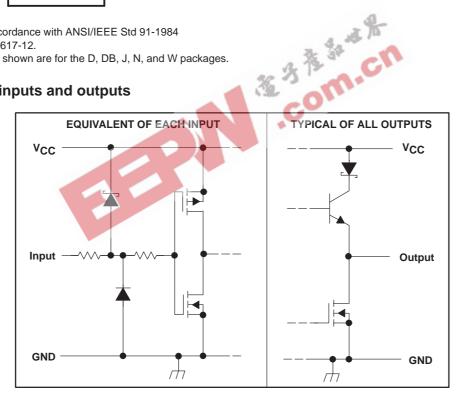
#### ΕN 12 2 1Y 1A — $\nabla$ 3 1Z $\nabla$ 6 2Y 2A 5 10 11 3Z 14 4Y 15 4A 13 4Z

# logic diagram (positive logic)



The terminal numbers shown are for the D, DB, J, N, and W packages.

## schematics of inputs and outputs





<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub> (see Note 1)	0.5 V to 7 V
Input voltage range, V <sub>I</sub>	0.5 V to V <sub>CC</sub> + 0.5 V
Differential input voltage range, V <sub>ID</sub>	
Output voltage range, V <sub>O</sub>	–0.5 V to 7 V
Input or output clamp current, I <sub>IK</sub> or I <sub>OK</sub>	±20 mA
Output current, IO	±150 mA
V <sub>CC</sub> current	200 mA
GND current	–200 mA
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T <sub>stq</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential output voltage (VOD), are with respect to the network ground terminal.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	_
DB	781 mW	6.2 mW/°C	502 mW	409 mW	_
N	1150 mW	9.2 mW/°C	736 mW	598 mW	_
FK	1375 mW	11 mW/°C	<u>C</u>	_	275 mW
J	1375 mW	11 mW/°C	_	_	275 mW
W	1000 mW	8.0 mW/°C	_	_	200 mW

### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.5	5	5.5	V
Differential input voltage, V <sub>ID</sub>			±7		V
High-level input voltage, VIH	High-level input voltage, VIH				V
Low-level input voltage, V <sub>IL</sub>	Low-level input voltage, V <sub>IL</sub>			0.8	V
High-level output current, IOH				-20	mA
Low-level output current, IOL				20	mA
	AM26C31C	0		70	
Operating free-air temperature, TA	AM26C31I	-40		85	°C
	AM26C31M	-55		125	

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#### electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	AM26C31C AM26C31I			UNIT	
			MIN	TYP	MAX		
Vон	High-level output voltage	$I_O = -20 \text{ mA}$	2.4	3.4		V	
VOL	Low-level output voltage	I <sub>O</sub> = 20 mA		0.2	0.4	V	
IVODI	Differential output voltage magnitude		2	3.1		V	
ΔIVODI	Change in magnitude of differential output voltage‡	D. 400 O. See Figure 4			±0.4	V	
Voc	Common-mode output voltage	$R_L$ = 100 Ω, See Figure 1			3	V	
ΔIVOCI	Change in magnitude of common-mode output voltage‡				±0.4	V	
II	Input current	V <sub>I</sub> = V <sub>CC</sub> or GND			±1	μΑ	
15.00	Driver output current with power off	$V_{CC} = 0$ , $V_{O} = 6 V$			100	μА	
IO(off)		$V_{CC} = 0$ , $V_{O} = -0.25 \text{ V}$			-100	μΑ	
los	Driver output short-circuit current	V <sub>O</sub> = 0	-30		-150	mA	
	High importance off state subject company	V <sub>O</sub> = 2.5 V			20	μΑ	
loz	High-impedance off-state output current	V <sub>O</sub> = 0.5 V			-20	μΑ	
		$I_O = 0$ , $V_I = 0 \text{ V or 5 V}$			100	μΑ	
ICC	Quiescent supply current	$I_{O} = 0$ , $V_{I} = 2.4 \text{ V or } 0.5 \text{ V}$ , See Note 2		1.5	3	mA	
C <sub>i</sub>	Input capacitance	135		6		pF	

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .

NOTE 2: This parameter is measured per input. All other inputs are at 0 or 5 V.

#### switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		AM26C31C AM26C31I			UNIT
					TYP <sup>†</sup>	MAX	
tPLH	Propagation delay time, low- to high-level output			3	7	12	ns
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	S1 is open,	See Figure 2	3	7	12	ns
<sup>t</sup> sk(p)	Pulse skew time ( tpLH - tpHL )	]			0.5	4	ns
$t_r(OD)$ , $t_f(OD)$	Differential output rise and fall times	S1 is open,	See Figure 3		5	10	ns
<sup>t</sup> PZH	Output enable time to high level				10	19	ns
t <sub>PZL</sub>	Output enable time to low level	S1 is closed,	See Figure 4		10	19	ns
<sup>t</sup> PHZ	Output disable time from high level	3 i is ciosed,	See Figure 4		7	16	ns
t <sub>PLZ</sub>	Output disable time from low level				7	16	ns
C <sub>pd</sub>	Power dissipation capacitance (each driver) (see Note 3)	S1 is open,	See Figure 2		170	·	pF

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .

NOTE 3:  $C_{pd}$  is used to estimate the switching losses according to  $P_D = C_{pd} \times V_{CC}^2 \times f$ , where f is the switching frequency.



<sup>‡</sup>Δ|VOD| and Δ|VOC| are the changes in magnitude of VOD and VOC, respectively, that occur when the input is changed from a high level to a low level.

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#### electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		AM26C31M			
	PARAMETER		TEST CONDITIONS		TYP <sup>†</sup>	MAX	UNIT
Vон	High-level output voltage	$I_0 = -20 \text{ mA}$		2.2	3.4		V
VOL	Low-level output voltage	$I_O = 20 \text{ mA}$			0.2	0.4	V
IVODI	Differential output voltage magnitude			2	3.1		V
Δ V <sub>OD</sub>	Change in magnitude of differential output voltage <sup>‡</sup>	D. 400.0	Coo Firms 4			±0.4	٧
Voc	Common-mode output voltage	$R_L = 100 \Omega$ ,	See Figure 1			3	V
ΔIVOCI	Change in magnitude of common-mode output voltage‡					±0.4	V
Ι <sub>Ι</sub>	Input current	$V_I = V_{CC}$ or (	GND			±1	μΑ
10.00	Driver and the second of the s		V <sub>O</sub> = 6 V			100	^
IO(off)	Driver output current with power off	VCC = 0,	$V_0 = -0.25 \text{ V}$			-100	μΑ
los	Driver output short-circuit current	VO = 0				-170	mA
lo-	High-impedance off-state output current	$V_0 = 2.5 V$	2_			20	μΑ
loz	nigh-impedance oil-state output current	V <sub>O</sub> = 0.5 V	4. 18. 14			-20	μΑ
loo	Quiescent supply current	$I_{O} = 0$ ,	V <sub>I</sub> = 0 V or 5 V			100	μΑ
Icc		IO = 0,	V <sub>I</sub> = 2.4 V or 0.5 V, See Note 2			3.2	mA
Ci	Input capacitance		132		6		pF

NOTE 2: This parameter is measured per input. All other inputs are at 0 V or 5 V.

#### switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CO	TEST CONDITIONS		AM26C31M		
	PARAMETER				TYP†	MAX	UNIT
tPLH	Propagation delay time, low- to high-level output				7	12	ns
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	S1 is open, See Figure 2			6.5	12	ns
tsk(p)	Pulse skew time ( tpLH - tpHL )				0.5	4	ns
tr(OD), tf(OD)	Differential output rise and fall times	S1 is open,	See Figure 3		5	12	ns
<sup>t</sup> PZH	Output enable time to high level				10	19	ns
tPZL	Output enable time to low level  Output disable time from high level  S1 is closed, See Figure 4			10	19	ns	
t <sub>PHZ</sub>			See Figure 4		7	16	ns
tPLZ	Output disable time from low level				7	16	ns
C <sub>pd</sub>	Power dissipation capacitance (each driver) (see Note 3)	S1 is open,	See Figure 2		100		pF

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .

NOTE 3:  $C_{pd}$  is used to estimate the switching losses according to  $P_D = C_{pd} \times V_{CC}^2 \times f$ , where f is the switching frequency.



<sup>†</sup> All typical values are at  $V_{CC}$  = 5 V and  $T_A$  = 25°C. ‡  $\Delta |V_{OD}|$  and  $\Delta |V_{OC}|$  are the changes in magnitude of  $V_{OD}$  and  $V_{OC}$ , respectively, that occur when the input is changed from a high level to a low level.

#### PARAMETER MEASUREMENT INFORMATION

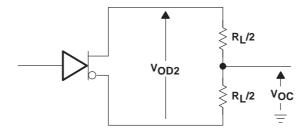
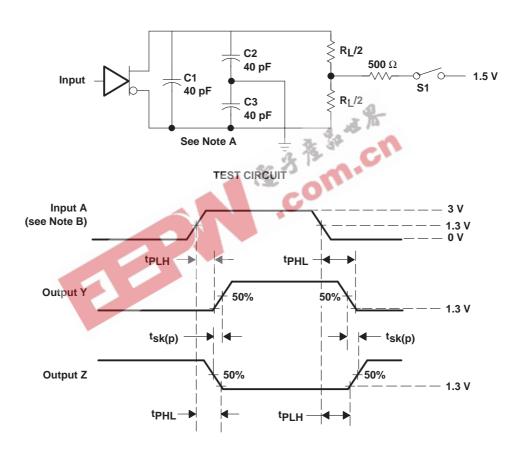


Figure 1. Differential and Common-Mode Output Voltages



NOTES: A. C1, C2, and C3 include probe and jig capacitance.

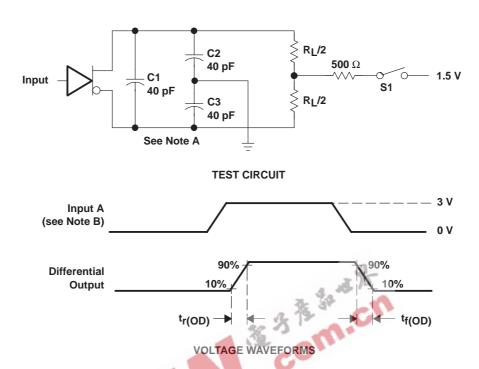
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, duty cycle ≤ 50%, and t<sub>f</sub> t<sub>f</sub> ≤ 6 ns.

Figure 2. Propagation Delay Time and Skew Waveforms and Test Circuit



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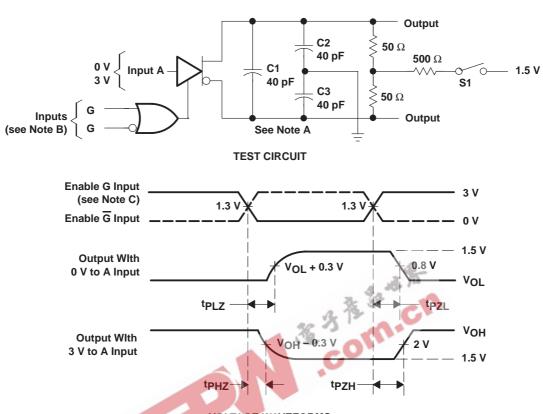
#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C1, C2, and C3 include probe and jig capacitance. B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, duty cycle  $\leq$  50%, and  $t_f$ ,  $t_f \leq$  6 ns.

Figure 3. Differential Output Rise and Fall Time Waveforms and Test Circuit

#### PARAMETER MEASUREMENT INFORMATION



**VOLTAGE WAVEFORMS** 

NOTES: A. C1, C2, and C3 includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, duty cycle  $\leq$  50%,  $t_{\Gamma}$  < 6 ns, and  $t_{\Gamma}$  < 6 ns.
- C. Each enable is tested separately.

Figure 4. Output Enable and Disable Time Waveforms and Test Circuit

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#### **TYPICAL CHARACTERISTICS**

# **SUPPLY CURRENT**

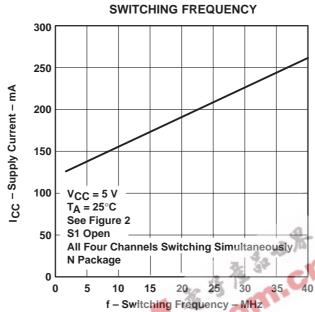


Figure 5

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